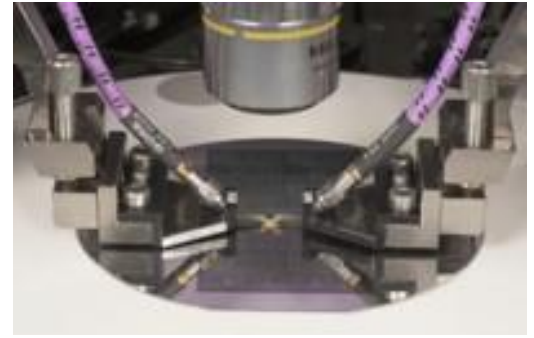


2nd PlanarCal Training Day

Venue: METAS, Bern, Switzerland
Date: 14 December 2017
Time: 09:00 hours to 18:00 hours



Registration is required!
For information and registration, please contact sekretariat@metas.ch.

This event is sponsored by the European Metrology Programme for Innovation and Research program (EMPIR) 'PlanarCal - 14IND02' Project (<http://planarcal.ptb.de>). The event is an informal seminar and free to attend. After an introduction to the VNA Tools software package and its new on-wafer functionality the seminar will feature oral presentations about recent developments and research results of the project.

TRAINING COURSE PROGRAM

09:00 - 09:20	Introduction	<i>Uwe Arz PTB, Germany</i>
09:20 - 10:30	Introduction to METAS UncLib and METAS VNATools	<i>Michael Wollensack METAS, Switzerland</i>
10:30 - 11:00	Coffee Break	
11:00 - 12:30	On-wafer measurements using VNA Tools (SOLT/LRM/LRRM)	<i>Michael Wollensack METAS, Switzerland</i>
12:30 - 13:30	Lunch	
13:30 - 13:55	Downsizing vector network analyzer measurements to nanoscale dimensions	<i>Faisal Mubarak VSL, The Netherlands</i>
13:55 - 14:25	Benefits and obstacles of planar on-wafer measurements at submillimeter frequencies	<i>Roger Lozar Fraunhofer IAF, Germany</i>
14:25 - 15:10	Reduction of parasitic effects and artifacts in MTRL calibration	<i>Gia Ngoc Phung Ferdinand-Braun-Institut, Germany</i>
15:10 - 15:40	Coffee Break	
15:40 - 16:05	110 GHz On-Wafer Measurement Comparison on Alumina Substrate	<i>Thorsten Probst PTB, Germany</i>
16:05 - 16:30	Establishing Traceability for On-Wafer S-Parameter Measurements of Membrane Technology Devices up to 110 GHz	<i>Uwe Arz PTB, Germany</i>
16:30 - 17:00	Round table discussion	
17:00 - 18:00	METAS lab tour?	